Special Editions of PDJ & Deposition of Supplemental Materials

One of the special features of *Powder Diffraction* (*PDJ*) is that it has for some years published the proceedings and select papers from several PXRD Conferences. The proceedings papers appear as digital papers (on-line only) in dedicated special editions of PDJ based on the time frame of the submission and editing the contributed papers. Near when this edition appears, the Proceedings of the European Powder Diffraction Conference, EPDIC-15, held in Bari, Italy, June 2016, will be published in *PDJ*. This biannual European Conference is focused on all aspects of the analysis of polycrystalline materials by diffraction methods. Shortly following publication of that special edition PDJ will subsequently publish the proceedings of the Australian X-ray Analytical Association's meeting, AXAA-2017, which was held in Melbourne, Australia, February 2017. The AXAA biannual conference focuses on X-ray diffraction, X-ray fluorescence, and synchrotron X-ray and neutron scattering. The Denver X-ray Conference, held in Chicago, USA in August 2016 provided a number of key papers that were jointly published in prior issues of *PDJ* and in the DXC-ICDD proceedings. The considerable number of excellent papers from these conference proceedings is a substantial augmentation to the contents and value of a subscription to *PDJ*. The conference attendees have free on-line access to these papers for 2 years, and *PDJ* subscribers also have full on-line access to the proceeding papers furthering the dissemination of the latest research results from experts around the world.

I also wish to draw attention to the value of Deposition of Supplemental Materials associated with papers in *PDJ*. The editors and I have been encouraging greater use of deposition of data and information that augments, but is not critically essential to, the paper. The three Technical Articles and most all of the New Diffraction Data papers in this edition include Supplemental Materials that should be valuable to those keenly interested to read deeper into the science and materials characterization reported in the paper. The supplemental materials frequently include a ".cif" file that contains the raw XRD data and detailed information related to data collection and processing and for Rietveld analyses the crystal structure parameters. Authors also make excellent use of Supplemental Materials to deposit additional Tables and Figures and or for extremely long table for the d-obs, 2Θ-obs, hkl, I-obs, d-calc, 2Θ-calc, and delta 2Θ for the phase being reported. Please check these out in this edition. Subscribers may access these files on-line via Cambridge Core (https://www.cambridge.org/core/journals/powder-diffraction) under the tab "Supplemental Materials" of the selected article abstract or select the link under "Supplemental Materials" located following the Conclusion Section in the article.

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Editor in Chief

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